

SOP-8 Plastic-Encapsulate MOSFETS

TF4840

N-Channel Enhancement Mode Power MOSFET

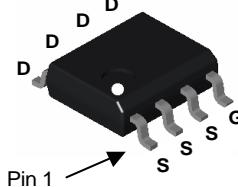
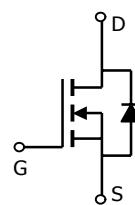
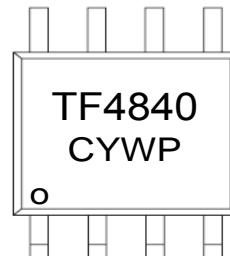
Description

The TF4840 uses advanced trench technology to provide excellent $R_{DS(on)}$ and low gate charge . The complementary MOSFETs may be used to form a level shifted high side switch, and for a host of other applications.

General Features

PRODUCT SUMMARY		
V _{DSS}	I _D	R _{DS(on)} (mΩ) Max
40V	15A	9 @ V _{GS} = 10V
		12 @ V _{GS} = 4.5V

- High power and current handing capability
- Lead free product is acquired
- Surface mount package

SOP-8L

Equivalent Circuit

MARKING


Y :year code W :week code

Absolute Maximum Ratings T_A=25°C unless otherwise noted

Parameter	Symbol	Maximum	Units
Drain-Source Voltage	V _{DS}	40	V
Gate-Source Voltage	V _{GS}	±20	V
Continuous Drain Current ^A	I _D	15	A
Pulsed Drain Current ^B	I _{DM}	45	
Power Dissipation ^A	P _D	3	W
		1.8	
Junction and Storage Temperature Range	T _J , T _{STG}	-55 to 150	°C

Thermal Characteristics

Parameter	Symbol	Typ	Max	Units
Maximum Junction-to-Ambient ^A	R _{θJA}	48	62.5	°C/W
Maximum Junction-to-Ambient ^A		74	110	°C/W
Maximum Junction-to-Lead ^C	R _{θJL}	35	40	°C/W



SHENZHEN TUOFENG SEMICONDUCTOR TECHNOLOGY CO.,LTD

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TF4840

Electrical Characteristics ($T_J=25^\circ\text{C}$ unless otherwise noted)

Symbol	Parameter	Conditions	Min	Typ	Max	Units
STATIC PARAMETERS						
BV_{DSS}	Drain-Source Breakdown Voltage	$I_D = 250\mu\text{A}, V_{GS}=0\text{V}$	40			V
I_{DSS}	Zero Gate Voltage Drain Current	$V_{DS}=40\text{V}, V_{GS}=0\text{V}$			100	nA
I_{GSS}	Gate-Body leakage current	$V_{DS}=0\text{V}, V_{GS}=\pm 20\text{V}$			± 100	nA
$V_{\text{GS}(\text{th})}$	Gate Threshold Voltage	$V_{DS}=V_{GS}, I_D = 250\mu\text{A}$	1.0	1.6	2.0	V
$I_{\text{D(ON)}}$	On state drain current	$V_{GS}=10\text{V}, V_{DS}=5\text{V}$	45			A
$R_{\text{DS(ON)}}$	Static Drain-Source On-Resistance	$V_{GS}=10\text{V}, I_D = 15\text{A}$		5	9	$\text{m}\Omega$
		$V_{GS}=4.5\text{V}, I_D = 15\text{A}$		10	12	$\text{m}\Omega$
g_{FS}	Forward Transconductance	$V_{DS}=15\text{V}, I_D = 15\text{A}$		42		S
V_{SD}	Diode Forward Voltage	$I_S = 10\text{A}, V_{GS}=0\text{V}$		0.8	1.2	V
I_S	Maximum Body-Diode Continuous Current				3	A

DYNAMIC PARAMETERS

C_{iss}	Input Capacitance	$V_{GS}=0\text{V}, V_{DS}=20\text{V}, f=1\text{MHz}$		1780		pF
C_{oss}	Output Capacitance			209		pF
C_{rss}	Reverse Transfer Capacitance			160		pF
R_g	Gate resistance	$V_{GS}=0\text{V}, V_{DS}=0\text{V}, f=1\text{MHz}$			9.5	Ω

SWITCHING PARAMETERS

$Q_g(10\text{V})$	Total Gate Charge (10V)	$V_{DD}=20\text{V}, V_{GEN}=10\text{V}, I_D=10\text{A}$		30		nC
$Q_g(4.5\text{V})$	Total Gate Charge (4.5V)			16.2		nC
Q_{gs}	Gate Source Charge			4.2		nC
Q_{gd}	Gate Drain Charge			9.5		nC
$t_{D(\text{on})}$	Turn-On Delay Time	$V_{DD}=20\text{V}, V_{GEN}=10\text{V}, R_L=2\Omega$ $R_{\text{GEN}}=3\Omega$		6.4		ns
t_r	Turn-On Rise Time			17.2		ns
$t_{D(\text{off})}$	Turn-Off Delay Time			29.8		ns
t_f	Turn-Off Fall Time			16.8		ns
t_{rr}	Body Diode Reverse Recovery Time	$I_F = 10\text{A}, dI/dt=100\text{A}/\mu\text{s}$		29		ns
Q_{rr}	Body Diode Reverse Recovery Charge	$I_F = 10\text{A}, dI/dt=100\text{A}/\mu\text{s}$		26		nC

A: The value of R_{0JA} is measured with the device mounted on 1in² FR-4 board with 2oz. Copper, in a still air environment with $T_A=25^\circ\text{C}$. The value in any given application depends on the user's specific board design. The current rating is based on the $t \leq 10\text{s}$ thermal resistance rating.

B: Repetitive rating, pulse width limited by junction temperature.

C. The R_{0JA} is the sum of the thermal impedance from junction to lead R_{0JL} and lead to ambient.

D. The static characteristics in Figures 1 to 6,12,14 are obtained using 80 μs pulses, duty cycle 0.5% max.

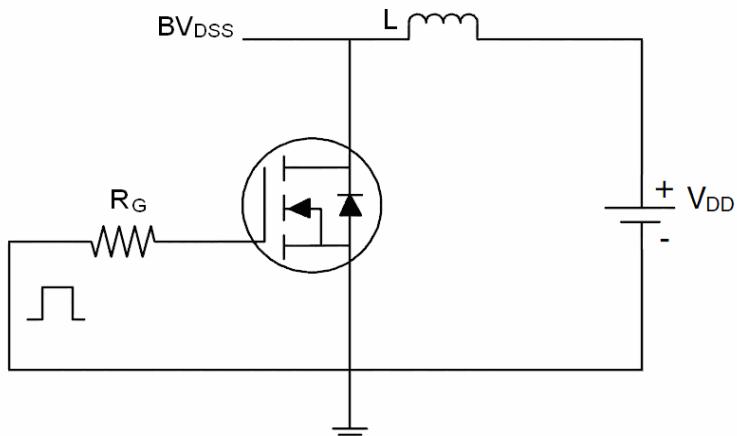
E. These tests are performed with the device mounted on 1 in² FR-4 board with 2oz. Copper, in a still air environment with $T_A=25^\circ\text{C}$. The SOA curve provides a single pulse rating.

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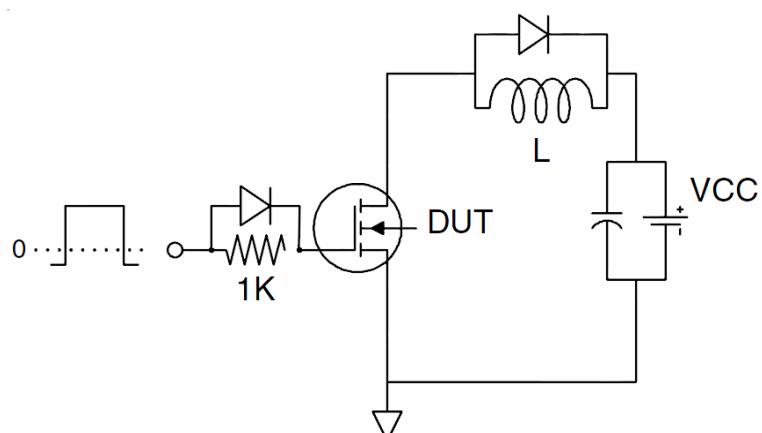
TF4840

Test circuit

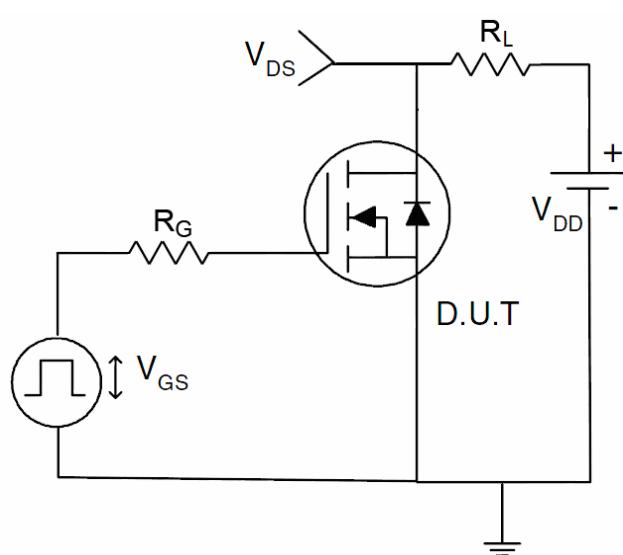
1) E_{AS} Test Circuit



2) Gate Charge Test Circuit



3) Switch Time Test Circuit



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Typical Electrical and Thermal Characteristics (Curves)

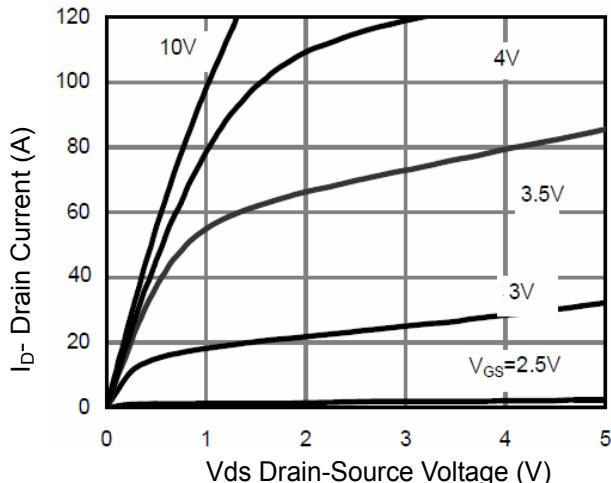


Figure 1 Output Characteristics

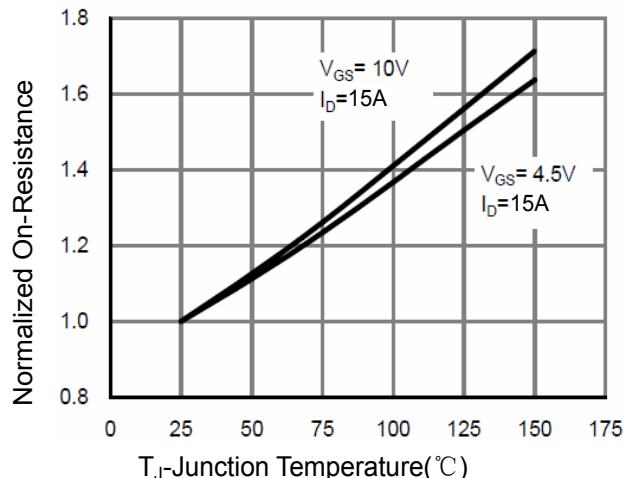


Figure 4 $R_{DS(on)}$ -Junction Temperature

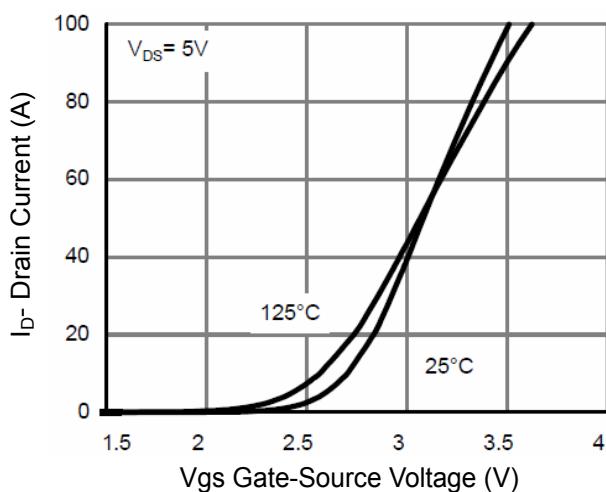


Figure 2 Transfer Characteristics

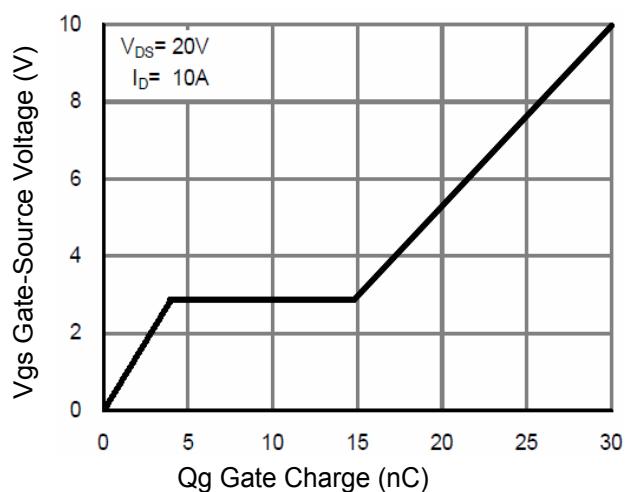


Figure 5 Gate Charge

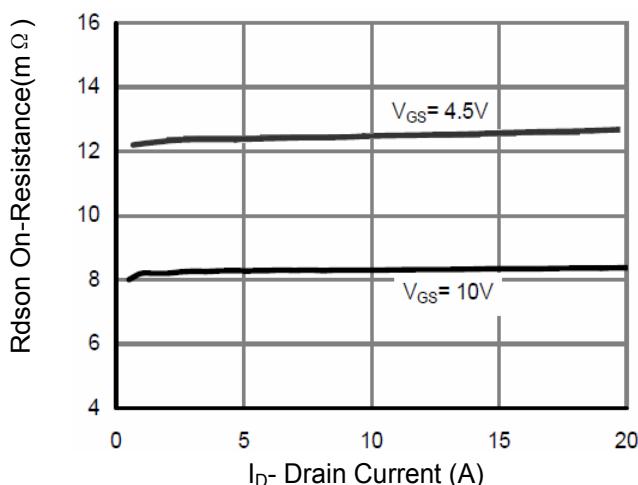


Figure 3 $R_{DS(on)}$ - Drain Current

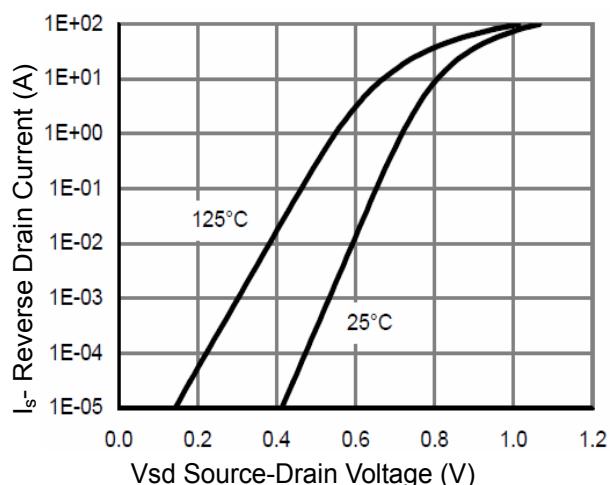


Figure 6 Source- Drain Diode Forward

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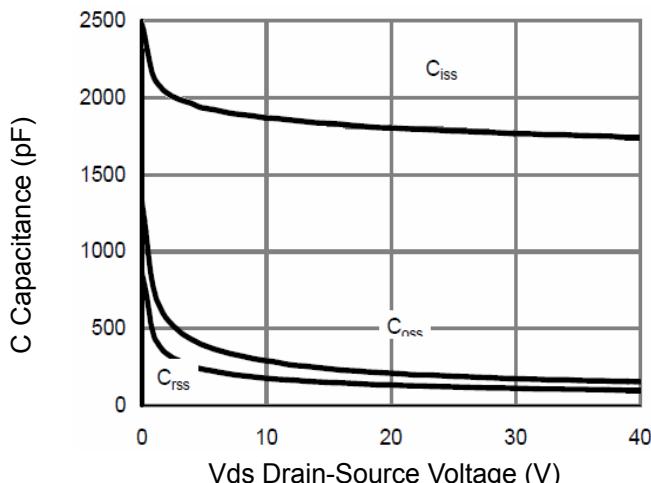


Figure 7 Capacitance vs V_{ds}

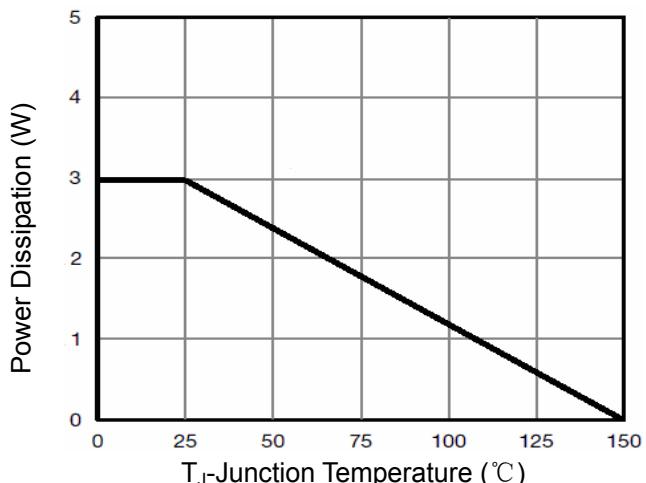


Figure 9 Power De-rating

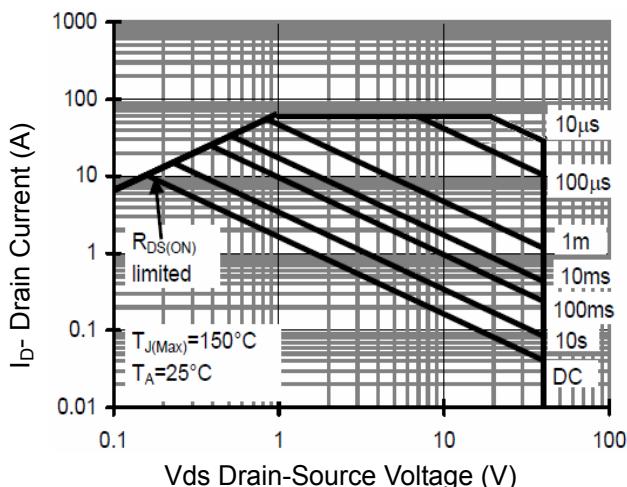


Figure 8 Safe Operation Area

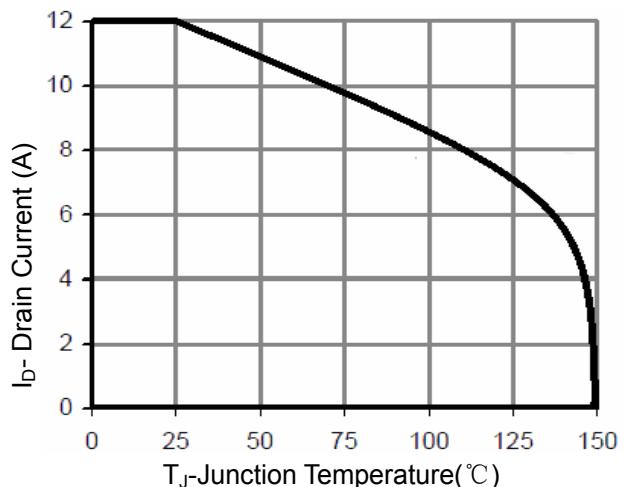


Figure 10 Current De-rating

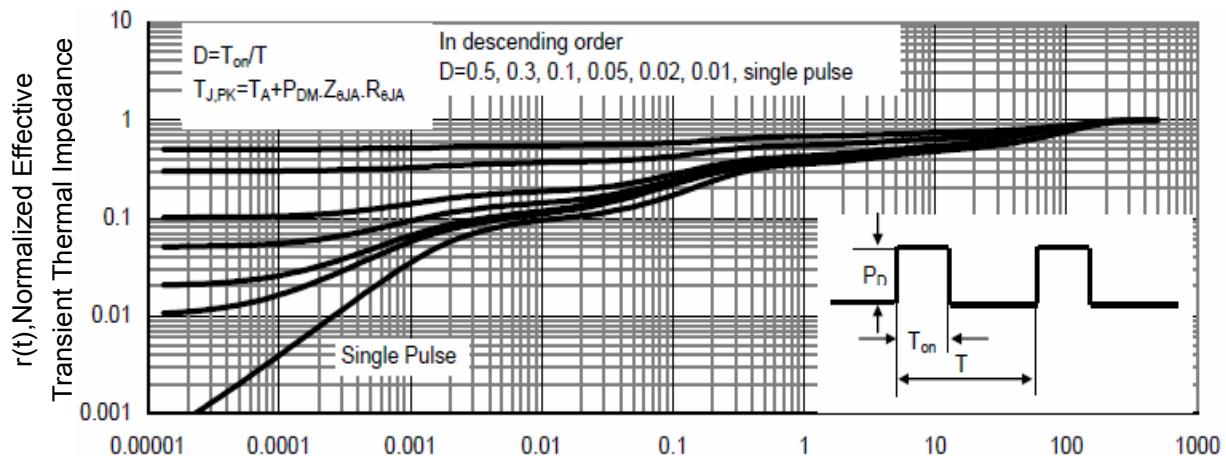
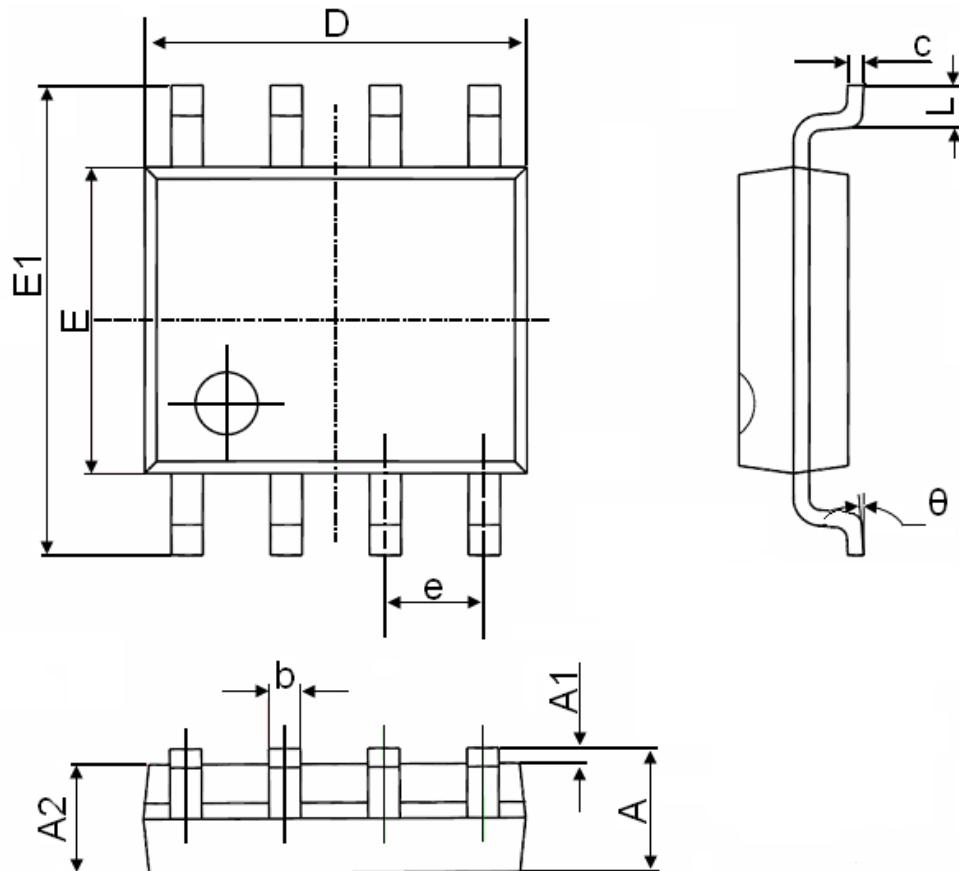


Figure 11 Normalized Maximum Transient Thermal Impedance

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SOP-8 Package Information



Symbol	Dimensions In Millimeters		Dimensions In Inches	
	Min.	Max.	Min.	Max.
A	1.350	1.750	0.053	0.069
A1	0.100	0.250	0.004	0.010
A2	1.350	1.550	0.053	0.061
b	0.330	0.510	0.013	0.020
c	0.170	0.250	0.006	0.010
D	4.700	5.100	0.185	0.200
E	3.800	4.000	0.150	0.157
E1	5.800	6.200	0.228	0.244
e	1.270(BSC)		0.050(BSC)	
L	0.400	1.270	0.016	0.050
θ	0°	8°	0°	8°